

Search Notes

Application/Control No.

10/517,040

Examiner

CUONG H. NGUYEN

Applicant(s)/Patent under
Reexamination

WEISS ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
701	2,24		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
DERWENT		
IEEE Xplore		
Inventors'names search		